

2024년 1월 24일(수)-26일(금) | 경주화백컨벤션센터(HICO)

2024년 1월 26일(금), 13:45-15:30 Room H(202),2층

K. Memory (Design & Process Technology) 분과

[FH2-K] Ferroelectric Memory I

좌장: 권용우 교수(홍익대학교), 정성엽 박사(차세대융합기술연구원)

FH2-K-1 13:45-14:00	Effect of Al Dopant Distribution in HfO ₂ Layer on Ferroelectric Switching Characteristics Hyoungjin Park ¹ , Seonuk Jeon ² , Hyun Wook Kim ² , Eunryeong Hong ² , Nayeon Kim ² , Yunsur Kim ¹ , Hyeonsik Choi ¹ , Jiae Jeong ¹ , and Jiyong Woo ^{1,2} ¹ School of Electronic Engineering, Kyungpook National University, ² School of Electronic and Electrical Engineering, Kyungpook National University
FH2-K-2 14:00-14:15	Novel Dual Ferroelectric Stack with Wide-range Tunable Coercive Voltage for High-density 3D FeNAND Applications Jiae Jeong ¹ , Nayeon Kim ² , Hyunwook Kim ² , Eunryeong Hong ² , Seonuk Jeon ² , Yunsur Kim ¹ , Hyeonsik Choi ¹ , Hyoungjin Park ¹ , and Jiyong Woo ^{1,2} ¹ School of Electronic Engineering, Kyungpook National University, ² School of Electronic and Electrical Engineering, Kyungpook National University
FH2-K-3 14:15-14:30	La ₂ O ₃ 중간층을 이용한 Ferroelectric FET 의 성능 및 내구성 개선 강창연, 추준홍, 김성호, 박영근, 김승훈, 조병진 한국과학기술원 전기 및 전자공학부
FH2-K-4 14:30-14:45	Enhancing Non-Volatile Memory Performance: Dual Ferroelectric Gate Field-Effect Transistors with Recessed Channel Geometry Simin Chen ¹ , Dae-Hwan An ² , Seong Ui An ¹ , Tae Hyeon Noh ¹ , and Younghyun Kim ¹ ¹ Department of Photonics and Nanoelectronics, BK21 FOUR ERICA-ACE Center, Hanyang University, ² Center for Opto-electronic Materials and Devices, KIST
FH2-K-5 14:45-15:00	Demonstration of Programmable Low-Temperature Hf-Based Ferroelectric Amorphous Oxide Semiconductor FET for Emerging Memory Applications Tae Hyeon Noh ¹ , Dae-Hwan Ahn ² , Hyo-Bae Kim ³ , Taewon Jin ¹ , Seoung min Park ¹ , Seong Ui An ¹ , Xinkai Sun ¹ , Simin Chen ¹ , Ji-Hoon Ahn ³ , and Younghyun Kim ¹ ¹ Department of Photonics and Nanoelectronics, BK21 FOUR ERICA-ACE Center, Hanyang University, ² Center for Opto-electronic Materials and Devices, KIST, ³ Department of Materials Science and Chemical Engineering, Hanyang University

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FH2-K-6 15:00-15:15	Analysis of Hydrogen Effect on Ferroelectric $(Hf,Zr)O_2$ Thin Films during Atomic Layer Deposition Process
	Seongbin Park ¹ , Seungbin Lee ¹ , Hye Ryeon Park ¹ , Jongmug Kang ¹ , Juntak Jeong ¹ ,
	Yeseo Choi ¹ , Jin-Hyun Kim ² , Minjong Lee ² , Jiyoung Kim ² , and Si Joon Kim ¹
	¹ Kangwon National University, ² The University of Texas at Dallas
	The Effect of Oxygen Vacancy Layer on Memory Performance of
FH2-K-7	Hafnia Ferroelectric Tunnel Junction
15:15-15:30	Junghyeon Hwang, Chaeheon Kim, Hunbeom Shin, and Sanghun Jeon
	School of Electrical Engineering, KAIST